

www.vishay.com

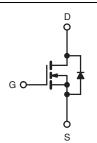
Vishay Siliconix

COMPLIANT

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	100				
$R_{DS(on)}(\Omega)$	$V_{GS} = 5.0 \text{ V}$	0.54			
Q _g (Max.) (nC)	6.1				
Q _{gs} (nC)	2.6				
Q _{gd} (nC)	3.3				
Configuration	Single				





N-Channel MOSFET

FEATURES

- · Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- For Automatic Insertion
- End Stackable
- Logic-Level Gate Drive
- R_{DS(on)} Specified at V_{GS} = 4 V and 5 V
- 175 °C Operating Temperature
- Material categorization: For definitions of compliance please see www.vishay.com/doc?99912

Note

* Lead (Pb)-containing terminations are not RoHS-compliant. Exemptions may apply.

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The 4 pin DIP package is a low cost machine-insertable case style which can be stacked in multiple combinations on standard 0.1" pin centers. The dual drain serves as a thermal link to the mounting surface for power dissipation levels up to 1 W.

ORDERING INFORMATION			
Package	HVMDIP		
Lead (Pb)-free	IRLD110PbF		
Leau (FD)-liee	SiHLD110-E3		
SnPb	IRLD110		
SIIFU	SiHLD110		

ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless otherwise noted)					
PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V _{DS}	100	V
Gate-Source Voltage			V_{GS}	± 10	\ \ \
Continuous Drain Current	V at 5.0.V	T _A = 25 °C T _A = 100 °C	- I _D	1.0	
	V _{GS} at 5.0 V	T _A = 100 °C		0.70	Α
Pulsed Drain Current ^a			I _{DM}	8.0	
Linear Derating Factor				0.0083	W/°C
Single Pulse Avalanche Energy ^b			E _{AS}	100	mJ
Avalanche Current ^a			I _{AR}	1.0	Α
Repetitive Avalanche Energy ^a			E _{AR}	0.13	mJ
Maximum Power Dissipation	T _A = 25 °C		P_{D}	1.3	W
Peak Diode Recovery dV/dtc			dV/dt	5.5	V/ns
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)	for	for 10 s		300 ^d	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 25 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 6.4 \,\text{mH}$, $R_g = 25 \,\Omega$, $I_{AS} = 5.6 \,\text{A}$ (see fig. 12).
- c. $I_{SD} \le 5.6$ A, $dI/dt \le 75$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 175$ °C.
- d. 1.6 mm from case.



Vishay Siliconix

THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	120	°C/W		

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static				L	L	L		
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA	-	0.12	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	· V _{GS} , I _D = 250 μA	1.0	-	2.0	V	
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 10 V	-	-	± 100	nA	
7 0		V _{DS} =	V _{DS} = 100 V, V _{GS} = 0 V		-	25		
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 80 \text{ V}$, V _{GS} = 0 V, T _J = 150 °C	-	-	250	μA	
D : 0	_	V _{GS} = 5.0 V	I _D = 0.60 A ^b	-	-	0.54		
Drain-Source On-State Resistance	$R_{DS(on)}$	V _{GS} = 4.0 V	I _D = 0.50 A ^b	-	-	0.76	Ω	
Forward Transconductance	9 _{fs}	V _{DS} =	50 V, I _D = 0.60 A ^b	1.3	-	-	S	
Dynamic				I.	I.	l .		
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	250	-		
Output Capacitance	C _{oss}		$V_{DS} = 0.0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		80	-	pF	
Reverse Transfer Capacitance	C _{rss}	f = 1.			15	-		
Total Gate Charge	Qg			-	-	6.1		
Gate-Source Charge	Q _{gs}	$V_{GS} = 5.0 \text{ V}$	$I_D = 5.6 \text{ A}, V_{DS} = 80 \text{ V},$ see fig. 6 and 13 ^b	-	-	2.6	nC	
Gate-Drain Charge	Q _{gd}		see fig. 6 and 13°		-	3.3	1	
Turn-On Delay Time	t _{d(on)}				9.3	-	ns	
Rise Time	t _r	V_{DD} = 50 V, I_{D} = 5.6 A, R_{g} = 12 Ω , R_{D} = 8.4 Ω , see fig. 10 ^b		-	4.7	-		
Turn-Off Delay Time	t _{d(off)}			-	16	-		
Fall Time	t _f			-	17	-		
Internal Drain Inductance	L _D	6 mm (0.25") f	Between lead, 6 mm (0.25") from		4.0	-	-11	
Internal Source Inductance	L _S	package and center of die contact		-	6.0	-	nH	
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.0	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	8.0		
Body Diode Voltage	V _{SD}	T _J = 25 °C	T _J = 25 °C, I _S = 1.0 A, V _{GS} = 0 V ^b		-	2.5	V	
Body Diode Reverse Recovery Time	t _{rr}	T 05 %C 1	E.C.A. dl/d+ 100 A/:h	-	110	130	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 5.6 \text{A}, \text{dI/dt} = 100 \text{A/} \mu \text{s}^{\text{b}}$		-	0.50	0.65	μC	
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time is negligible (turn	on is dor	ninated b	y L _S and	L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

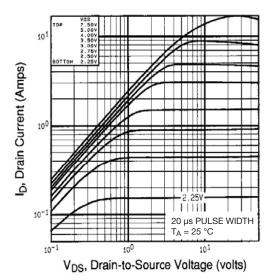


Fig. 1 - Typical Output Characteristics, T_A = 25 °C

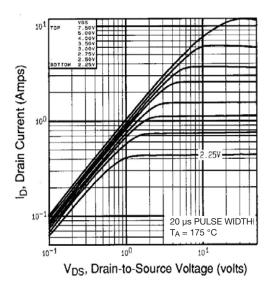


Fig. 2 - Typical Output Characteristics, T_A = 175 °C

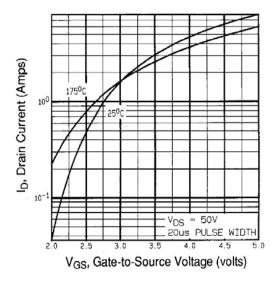


Fig. 3 - Typical Transfer Characteristics

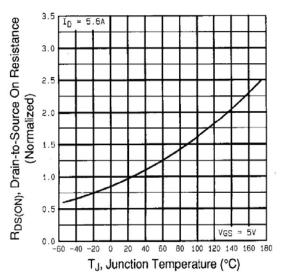


Fig. 4 - Normalized On-Resistance vs. Temperature



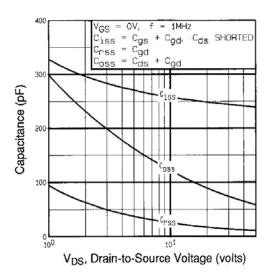


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

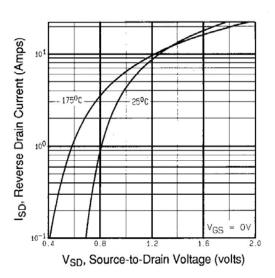


Fig. 7 - Typical Source-Drain Diode Forward Voltage

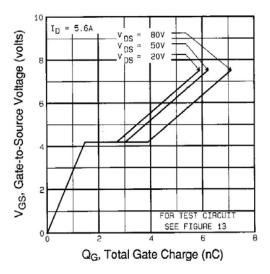


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

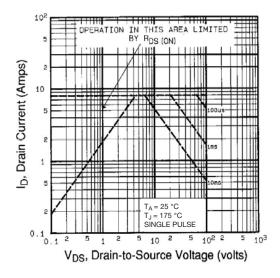


Fig. 8 - Maximum Safe Operating Area



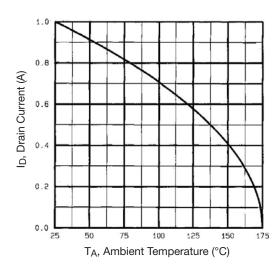


Fig. 9 - Maximum Drain Current vs. Ambient Temperature

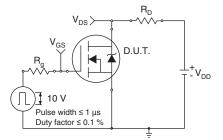


Fig. 10 - Switching Time Test Circuit

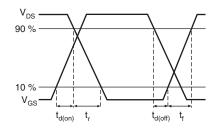


Fig. 11 - Switching Time Waveforms

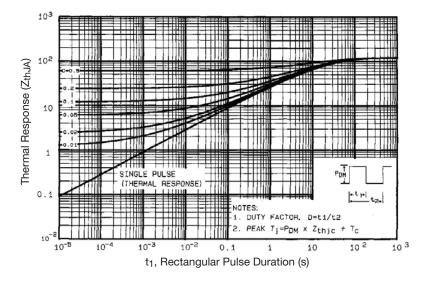


Fig. 12 - Maximum Effective Transient Thermal Impedance, Junction-to-Ambient



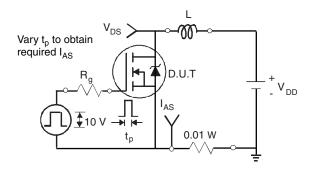


Fig. 13 - Unclamped Inductive Test Circuit

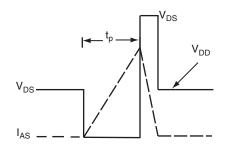


Fig. 14 - Unclamped Inductive Waveforms

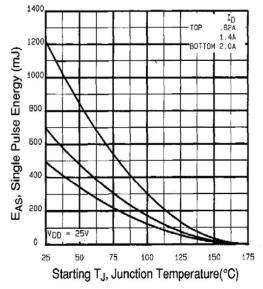


Fig. 15 - Maximum Avalanche Energy vs. Drain Current

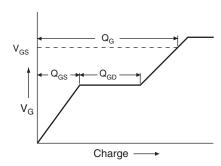


Fig. 16 - Basic Gate Charge Waveform

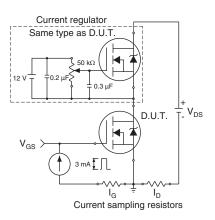
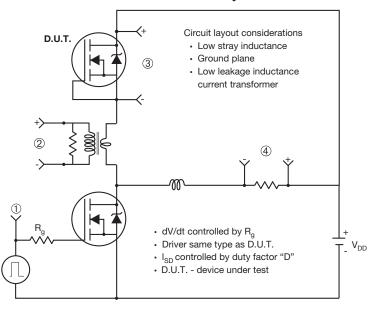


Fig. 17 - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



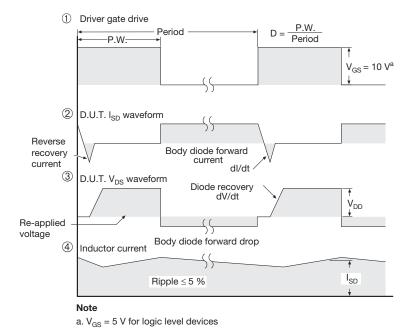
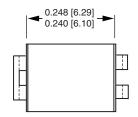


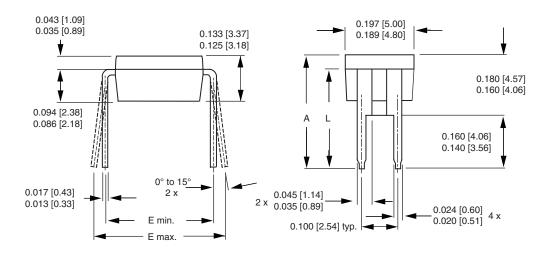
Fig. 18 - For N-Channel

Vishay Siliconix maintains worldwide manufacturing capability. Products may be manufactured at one of several qualified locations. Reliability data for Silicon Technology and Package Reliability represent a composite of all qualified locations. For related documents such as package/tape drawings, part marking, and reliability data, see www.vishay.com/ppg?91309.

Vishay Siliconix

HVM DIP (High voltage)





	INCHES		INCHES MILLIMETERS		IETERS
DIM.	MIN.	MAX.	MIN.	MAX.	
A	0.310	0.330	7.87	8.38	
Е	0.300	0.425	7.62	10.79	
L	0.270	0.290	6.86	7.36	

ECN: X10-0386-Rev. B, 06-Sep-10

DWG: 5974

Note

1. Package length does not include mold flash, protrusions or gate burrs. Package width does not include interlead flash or protrusions.

Document Number: 91361 Revision: 06-Sep-10



Legal Disclaimer Notice

Vishay

Disclaimer

ALL PRODUCT, PRODUCT SPECIFICATIONS AND DATA ARE SUBJECT TO CHANGE WITHOUT NOTICE TO IMPROVE RELIABILITY, FUNCTION OR DESIGN OR OTHERWISE.

Vishay Intertechnology, Inc., its affiliates, agents, and employees, and all persons acting on its or their behalf (collectively, "Vishay"), disclaim any and all liability for any errors, inaccuracies or incompleteness contained in any datasheet or in any other disclosure relating to any product.

Vishay makes no warranty, representation or guarantee regarding the suitability of the products for any particular purpose or the continuing production of any product. To the maximum extent permitted by applicable law, Vishay disclaims (i) any and all liability arising out of the application or use of any product, (ii) any and all liability, including without limitation special, consequential or incidental damages, and (iii) any and all implied warranties, including warranties of fitness for particular purpose, non-infringement and merchantability.

Statements regarding the suitability of products for certain types of applications are based on Vishay's knowledge of typical requirements that are often placed on Vishay products in generic applications. Such statements are not binding statements about the suitability of products for a particular application. It is the customer's responsibility to validate that a particular product with the properties described in the product specification is suitable for use in a particular application. Parameters provided in datasheets and / or specifications may vary in different applications and performance may vary over time. All operating parameters, including typical parameters, must be validated for each customer application by the customer's technical experts. Product specifications do not expand or otherwise modify Vishay's terms and conditions of purchase, including but not limited to the warranty expressed therein.

Except as expressly indicated in writing, Vishay products are not designed for use in medical, life-saving, or life-sustaining applications or for any other application in which the failure of the Vishay product could result in personal injury or death. Customers using or selling Vishay products not expressly indicated for use in such applications do so at their own risk. Please contact authorized Vishay personnel to obtain written terms and conditions regarding products designed for such applications.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted by this document or by any conduct of Vishay. Product names and markings noted herein may be trademarks of their respective owners.